

**Search Notes**

Application/Control No.

09/663,811

Examiner

Shin-Hon Chen

Applicant(s)/Patent under  
Reexamination

HACHERL ET AL.

Art Unit

2131

**SEARCHED**

Class	Subclass	Date	Examiner
726	3	4/20/2006	S.C.
709	229	4/20/2006	S.C.

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
USPAT, PGPUB, JPO,EPO, DERWENT	4/20/2006	S.C.